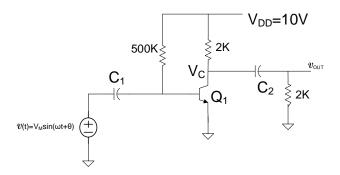
EE 330 Homework 9 Spring 2018

Due Wed March 7 at the beginning of class (no late HW accepted)

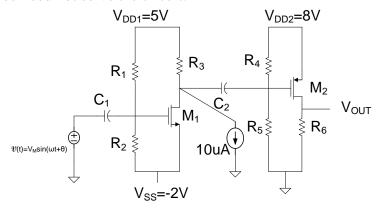
All problems are worth 10 points except Problems 8-9 which are worth 20 points. Unless specified to the contrary, assume all n-channel MOS transistors have model parameters $\mu_n C_{OX} = 350 \mu A/V^2$ and $V_{Tn} = 0.5 V$, all p-channel transistors have model parameters $\mu_p C_{OX} = 70 \mu A/V^2$ and $V_{Tp} = -0.5 V$. Correspondingly, assume all npn BJT transistors have model parameters $J_S = 10^{-14} A/\mu^2$ and $\beta = 100$ and all pnp BJT transistors have model parameters $J_S = 10^{-14} A/\mu^2$ and $\beta = 25$. If the emitter area of a transistor is not given, assume it is $100 \mu^2$. If parameters are needed for CMOS process characterization beyond what is given, use the measured parameters from the TSMC 0.18 μ process given below as model parameters. Assume all diodes are characterized by the model parameters $J_{SX} = 0.5 A/\mu m^2$, $V_{G0} = 1.17 V$, and m = 2.3.

Problem 1 Assume the capacitors are very large and V_M is small.

- a) Draw the small signal equivalent circuit for the amplifier shown
- b) Determine the quiescent value of V_C and V_{OUT}
- c) Determine the voltage gain in terms of the small-signal y-parameters for the transistor. Assume the parameter y_{21} in the model of the transistor is 0.



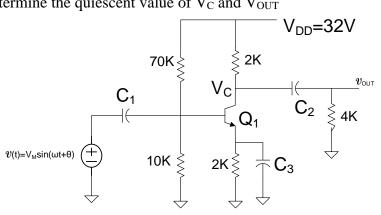
Problem 2 Obtain the small signal equivalent circuit for the following network. Assume the transistors are operating in the saturation region, all capacitors are large, and V_M is small. You need not solve the circuit.



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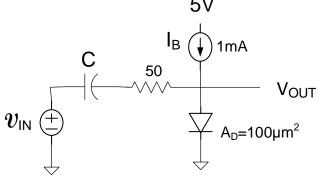
Problem 3 Assume the capacitors are all very large and V_m is small.

- a) Draw the small signal equivalent circuit for the amplifier shown
- b) Determine the quiescent value of V_C and V_{OUT}



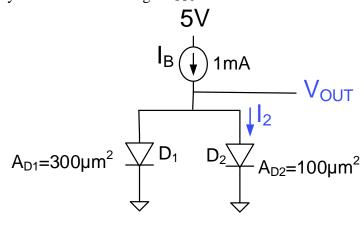
Problem 4 Consider the following circuit operating at T=300K. Assume the capacitor C is very large and the $v_{\rm IN}$ is a small-signal input.

- a) Determine the quiescent output voltage.
- b) Draw the small-signal equivalent circuit
- c) Determine the small-signal voltage gain from the input to the output.
- d) Repeat part c) if the current I_B is increased to 5mA



Problem 5 Consider the following circuit operating at T=300K.

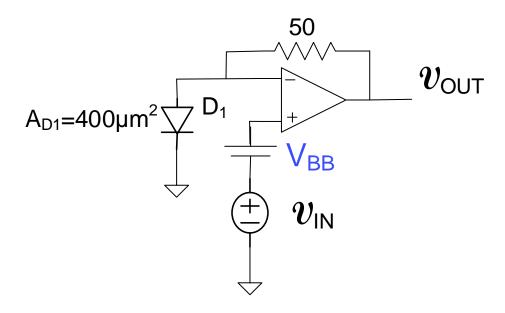
- a) Determine I₂
- b) Accurately determine the voltage V_{OUT}



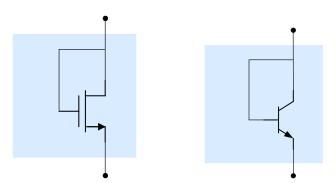
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Problem 6 Consider the following circuit operating at T=300K. Assume $v_{\rm IN}$ is a small-signal voltage source.

- a) If the voltage V_{BB} is adjusted so that the quiescent diode current is 1mA, determine the small signal voltage gain $A_V = \frac{v_{OUT}}{v_{DU}}$
- b) Repeat part a) if V_{BB} is adjusted so that the quiescent diode current is 10mA



Problem 7 Obtain the small signal impedance between the two terminals exiting the box. Assume the MOSFET is operating in the Saturation region and the BJT in the Forward Active region and that the quiescent currents are both 1mA.



Problems 8-9 Use Modelsim to create a 4-bit register. The register should only change its value on a positive clock edge. Include an enable bit and make the register only change its's value if the enable bit is high during the positive clock edge. Create a test bench to test the correct operation of the register. Include screenshots of your Verilog code, and simulation waveforms.

MOSIS WAFER ACCEPTANCE TESTS

RUN: T68B (MM NON-EPI) VENDOR:

TSMC

TECHNOLOGY: SCN018 FEATURE SIZE: 0.18

microns

Run type: SKD

INTRODUCTION: This report contains the lot average results obtained by MOSIS from measurements of MOSIS test structures on each wafer of this fabrication lot. SPICE parameters obtained from similar measurements on a selected wafer are also attached.

COMMENTS: DSCN6M018 TSMC

TRANSISTOR PARAMETERS	W/L	N-CHANNEL	P-CHANNEL	UNITS
MINIMUM Vth	0.27/0.18	0.50	-0.51	volts
SHORT Idss Vth Vpt	20.0/0.18	547 0.51 4.8	-250 -0.51 -5.6	uA/um volts volts
WIDE Ids0	20.0/0.18	14.4	-4.7	pA/um
LARGE Vth Vjbkd Ijlk	50/50	0.43 3.1 <50.0	-4.3	volts volts pA
K' (Uo*Cox/2) Low-field Mobility		175.4 416.5		uA/V^2 4 cm^2/V*s

COMMENTS: Poly bias varies with design technology. To account for mask bias use the appropriate value for the parameters XL and XW in your SPICE model card.

in your SPI	CE model car	rd.					
	Design Technology			L (um)	XW um)		
	SCN6M_DEEP	(lambda=0.09	9) 0	.00	-0.01		
		thick oxid	de 0	.00	-0.01		
	SCN6M_SUBM	(lambda=0.10	- 0	.02	0.00		
		thick oxid	de -0	.02	0.00		
FOX TRANSISTORS	GATE	N+ACTIVE	P+ACTIVE	UNITS			
Vth	Poly	>6.6	<-6.6	volts			

PROCESS PARAMETERS N+ P+ POLY N+BLK PLY+BLK M1 M2 UNITS

Sheet Resistance 6.7 7.8 8.0 59.7 313.6 0.08 0.08 ohms/sq Contact Resistance 10.6 11.0 10.0 4.79 ohms
Gate Oxide Thickness 41 angstrom

 PROCESS PARAMETERS
 M3
 POLY_HRI
 M4
 M5
 M6
 N_W
 UNITS

 Sheet Resistance
 0.08
 0.08
 0.08
 0.03
 930
 ohms/sq

 Contact Resistance
 9.24
 14.05
 18.39
 20.69
 ohms

COMMENTS: BLK is silicide block.

Area (substrate) 942 1163 106 34 14 9 6 5 3 123 125 aF/um^2 Area (N+active) 8484 55 20 13 11 9 8 aF/um^2 Area (P+active) 8232 aF/um^2 Area (poly) 66 17 10 7 5 4 aF/um^2
Area (P+active) 8232 aF/um^2 Area (poly) 66 17 10 7 5 4 aF/um^2
Area (poly) 66 17 10 7 5 4 aF/um^2
0.000
Area (metal1) 37 14 9 6 5 aF/um^2
Area (metal2) 35 14 9 6 aF/um^2
Area (metal3) 37 14 9 aF/um^2
Area (metal4) 36 14 aF/um^2
Area (metal5) 34 984 aF/um^2
Area (r well) 920 aF/um^2
Area (d well) 582 aF/um^2
Area (no well) 137 aF/um^2
Fringe (substrate) 212 235 41 35 29 21 14 aF/um
Fringe (poly) 70 39 29 23 20 17 aF/um
Fringe (metal1) 52 34 22 19 aF/um
Fringe (metal2) 48 35 27 22 aF/um
Fringe (metal3) 53 34 27 aF/um
Fringe (metal4) 58 35 aF/um
Fringe (metal5) 55 aF/um
Overlap (N+active) 895 aF/um
Overlap (P+active) 737 aF/um

		UNITS
K		
1.0	0.74	volts
1.5	0.78	volts
2.0	0.08	volts
2.0	1.63	volts
2.0	0.82	volts
2.0	-23.72	
	300.36	MHz
	363.77	MHz
	0.07	uW/MHz/gate
	0.02	uW/MHz/gate
	1.0 1.5 2.0 2.0	1.0 0.74 1.5 0.78 2.0 0.08 2.0 1.63 2.0 0.82 2.0 -23.72 300.36 363.77